Hybrid 8j365 Traveler

May 26, 2000

1 Connectivity

Repairs on shorts:
Fixes for opens:

2 Chips

The following chips were assembled on this hybrid (in the order that the chips get read out):
Hybrid 8J365 has die: 168-121 168-122 168-123 168-124 206-090 206-093 206-094 206-095

3 Data Analysis Summary

The following summarizes the findings of the Burn-in data analysis program. The first chip in the readout name is numbered 0.

```
% Hybrid 8j365 classification info. Created 10:50:47 05/24/00

Hybrid 8j365 quality: bad
Chip classification: good good good good bad good fair good
Bad channels (chip-channel): 4-109 4-121 4-122 4-123 6-53
Bad cells: none
Random bad capacitors (chip-cell-channel): 4-20-122 6-44-50
Channels at pedestal needed for DCMS: 36.4 33.6 33.6 32.6 29.7 30.6 29.8 30.6
```

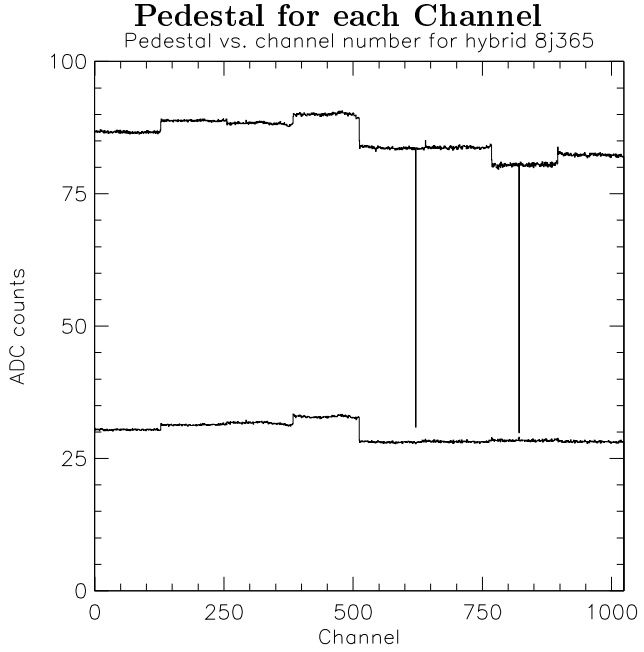
4 Comments

HV tested.

5 Pedestal

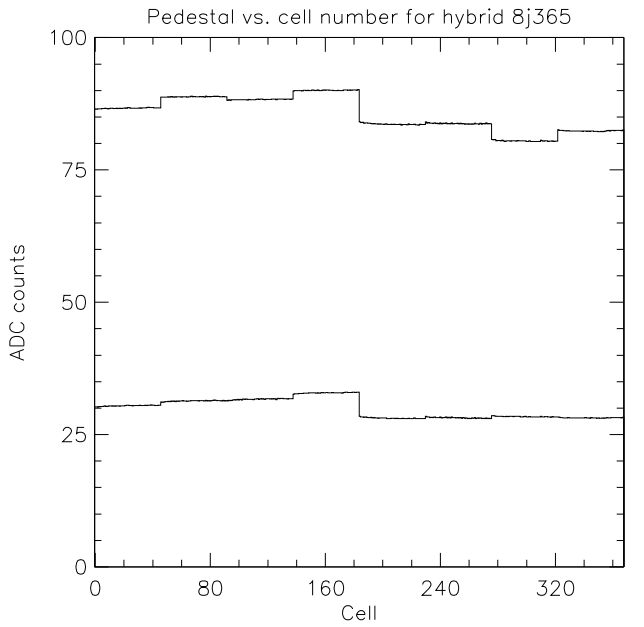
The following plot shows the pedestals vs. channel number with and without charge injection:

Pedestal for each Channel



The following plot shows the average pedestal vs. pipeline cell ID with and without charge injection. The x-axis is cell ID offset by 46 for each chip. Thus cell ID 5 for chip 1 is at x=5, chip 2 at x=51, chip 3 at x=97, etc.

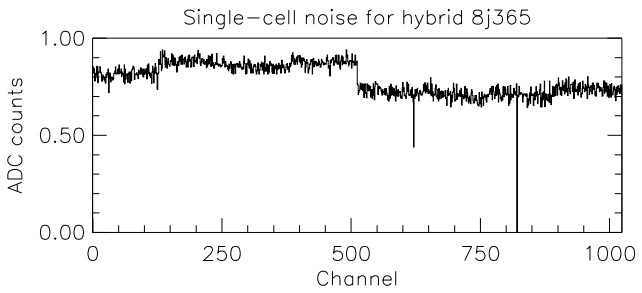
Pedestal vs. Pipeline Cell ID

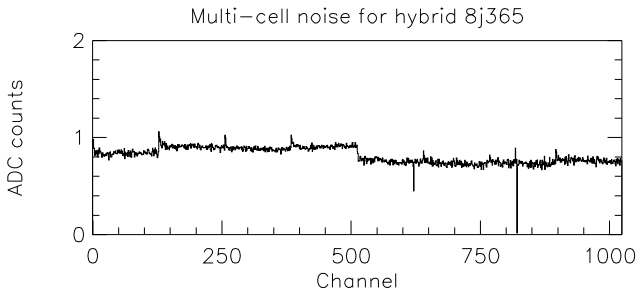


6 Noise

The following plots show the single-cell and multi-cell RMS noise:

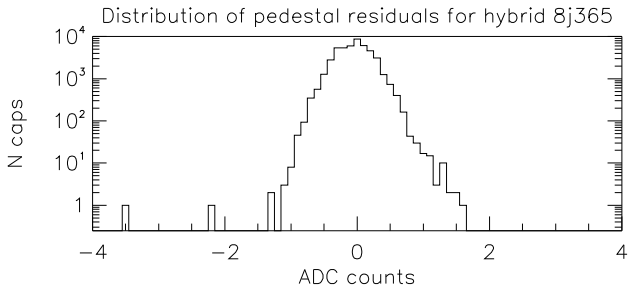
RMS Noise

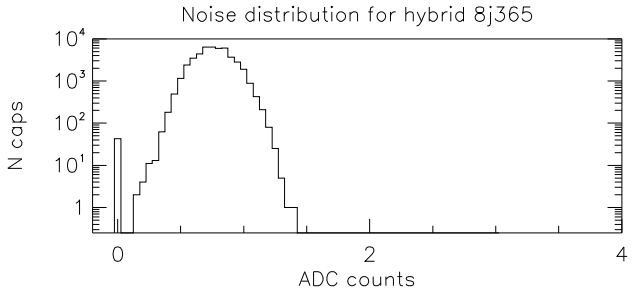




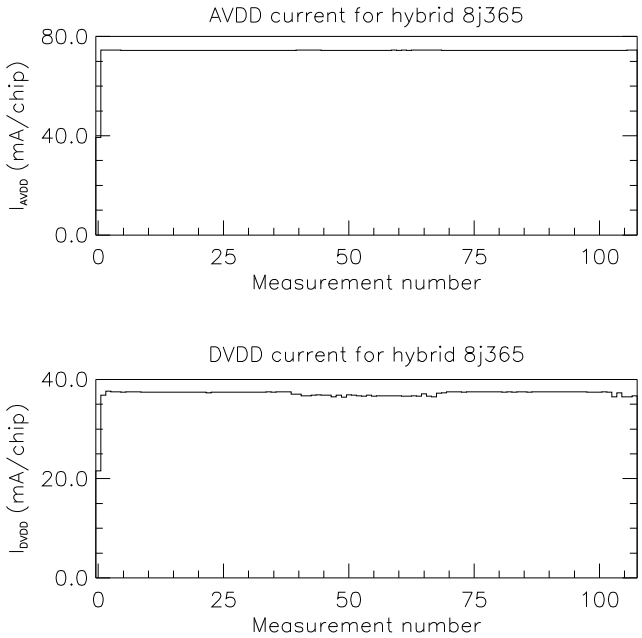
The following are histograms of the pedestal of each pipeline capacitor relative to the chip average (top); and the RMS noise of each capacitor (bottom):

Distribution of Pedestals and Noise





7 Currents

The following plots show the supply currents per chip as a function of measurment number. Currents are measured approximately every 10 minutes:

Supply Currents During Burn-in